g		GE Energy		Functional Testing Specification						
	Renewal Serv			LOU-GEF-IC610CPUxxx						
	Louisville, KY									
		Test Procedu	ure for: IC6100	CPUXXX						
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Functional test procedure for: IC610CPUXXX

### 1. SCOPE

1.1 This is a functional testing procedure for a: Test Procedure.doc

## 2. STANDARDS OF QUALITY

2.1 Refer to the current revision of the IPC-A-610 standard for workmanship standards.

## 3. APPLICABLE DOCUMENTS

3.1 The following document(s) shall form part of this specification to the extent specified herein. Unless otherwise indicated, the latest issue shall apply.
2.1.1

## 4. ENGINEERING REQUIREMENTS

- 4.1 Equipment Cleaning
  - **4.1.1** Equipment should be clean and free of debris prior to applying power unless performing an initial check. Refer to the local documented procedures for cleaning guidelines.
- 4.2 Equipment Inspection
  - **4.2.1** Equipment should be visually inspected for any defects prior to applying power. This inspection should include the following as a minimum:
    - 4.2.1.1 Wires broken or cracked
    - 4.2.1.2 Terminal strips / connectors broken or cracked
    - **4.2.1.3** Loose wires
    - 4.2.1.4 Components visually damaged
    - 4.2.1.5 Capacitors leaking
    - 4.2.1.6 Solder joints damaged or cold
    - 4.2.1.7 Circuit board burned or de-laminated
    - 4.2.1.8 Printed wire runs burned or damaged

## 5. EQUIPMENT REQUIRED

**5.1** The following equipment is required to perform the process requirements. Equipment may be substituted provided that all accuracy's and test ratios are equivalent or better.

Qty	Reference #	Description	
1		Series One I/O Panel	
1		Portable Programmer	

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Clear Shift

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THIS CLEARS THE MEMORY

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# 6. <u>TESTING PROCESS</u>

## 6.1 Setup

- **6.1.1** Replaced RAM and battery.
- **6.1.2** Install CPU into Series One Rack and install programmer onto CPU.
- **6.1.3** Turn power on and turn key switch on programmer panel to Program.
- **6.1.4** Flip all switches to the down position.

348 Delete Next

**6.1.5** Install the following program into CPU using the portable programmer. Clear memory first then start with the 1<sup>st</sup> Bit

1st Bit	STR Timer			Enter Enter		600 Enter 10 Enter	Shift	1 Enter
2nd Bit	 STR Timer			Enter Enter		601 Enter 11 Enter	Shift	1 Enter
3rd Bit	 STR Timer		2 602			602 Enter 12 Enter	Shift	1 Enter
4th Bit	STR Timer		3 603	Enter Enter		603 Enter 13 Enter	Shift	1 Enter
5th Bit	 STR Timer			Enter Enter		604 Enter 14 Enter	Shift	1 Enter
6th Bit	STR Timer			Enter Enter		605 Enter 15 Enter	Shift	1 Enter
7th Bit	STR Timer		6 606	Enter Enter		606 Enter 16 Enter	Shift	1 Enter
8th Bit	 STR Timer	Shift Shift	-	Enter Enter		607 Enter 17 Enter	Shift	1 Enter
9th Bit	 STR Timer			Enter Enter		610 Enter 20 Enter	Shift	1 Enter
10th Bit	 STR Timer			Enter Enter		611 Enter 21 Enter	Shift	1 Enter

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11th Bit						612 Enter 22 Enter	Shift	1 Enter
12th Bit	STR Timer	_		Enter BEnter		613 Enter 23 Enter	Shift	1 Enter
13th Bit	_	_	_			614 Enter 24 Enter	Shift	1 Enter
14th Bit	_	Shift Shift				615 Enter 25 Enter	Shift	1 Enter
15th Bit		Shift Shift				616 Enter 26 Enter	Shift	1 Enter
16th Bit	STR Timer	_	_	Enter 7Enter	 - I	617 Enter 27 Enter		1 Enter

# 6.2 <u>Testing Procedure</u>

- **6.2.1** Once done you should see a End of Program statement.
- **6.2.2** Turn key switch to RUN.
- **6.2.3** Flip switch 000 up and approximately 1-second later light 010 should come on. The other switches should follow this same pattern.
- **6.2.4** If unit passes test, power down and remove card.
- **6.2.5** Reinstall master CPU, End of Test
- **6.3** \*\*\*TEST COMPLETE \*\*\*

# 7. <u>NOTES:</u>

8.